



^{conditions,} please se^c





SINGLE CRYSTAL DIFFRACTOMETRY

- Flexible goniometer (Eulerian cradle and various fixed chi, horizontal & vertical setups)
- Sphere of confusion < 0.005 mm (radius)
- State of the art interface
- Various sources (Microfocus BDS etc.)
- Ultrafast hybrid pixel detectors

STADIVARI

RAPID, COMPREHENSIVE AND EXTREMELY VERSATILE ANALYSIS OF A WIDE VARIETY OF MATERIALS

SOURCES

- Standard sealed tubes (Ag, Mo, Cu)
- Conventional & High Performance Microfocus sources (Ag, Mo, Cu)
- Metaljet liquid-metal-jet anode x-ray source
- Rotating anodes or synchroton

OPEN EULERIAN CRADLE

- High precision
- Sphere of confusion0.005 mm (radius)
- Virtually maintenance-free
- State of the art interface
- Sufficient completeness up to 150°

NEW DETECTOR GENERATION

- Dectris Pilatus 100K, 200K, 300K and Eiger pixel detectors
- CMOS hybrid-pixel technology
- Single-photon-counting mode
- No dark current
- Ultra-fast data collection as well as ultra-long exposure times



With the possibility to be set-up vertically as well as horizontally, the **STADIVARI** increases its scope of application. The **STADIVARI** can be used for single crystal and powder diffraction. The Open Eulerian Cradle offers enough space to add high

pressure cells, high- or low-temperature devices or other chambers. As the youngest member of the long line of STOE diffractometers, the **STADIVARI** is fully integrated in the well-established STOE X-Area software package.

FLEXIBLE GONIOMETER SETUP

- Eulerian Cradle
- Horizonta
- Vertica
- Inverted (
- Fixed Chi







DOUBLE BEAM SETUP

Various combinations possible:

- Standard Sealed Tubes
- Conventional Microfocus Sources
- High Performance Microfocus Sources





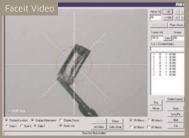
HEATSTREAM

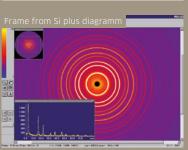
- Temperature range from RT to 1000K
- Temperature accuracy within +/-1°
- Heating medium N2 (open flow)
- Vertical gas flow for optimal sample heating

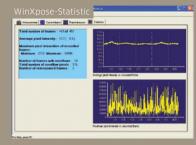


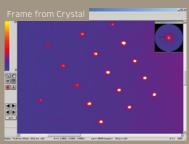
X-Area

- Software for easy data collection and evaluation
- Powerful solution for complicated situations (multi-domain and modulated crystals)
- Support for DACs











SYSTEM SPECIFICATIONS

Dimensions (including system cabinet, max.)	1680×1150×2050mm	
Weight (complete system)		
Sphere of confusion		
Goniometer (utilized angular regions)	2θ:240° / ω:205° / X:90° / Φ:360°	
Detector distance	40 - 140 mm (automatically set)	
X-ray sources	Standard sealed tubes (Ag, Mo, Cu), Conventional and High Performance Microfocus sources (Ag, Mo, Cu), MetalJet, rotating anodes or synchroton	

DETECTOR SPECIFICATIONS	PILATUS3 R 200K-A	PILATUS3 R 300K
Sensor	Reverse-biased silicon diode array	Reverse-biased silicon diode array
Sensor thickness	450 μm / 1000 μm	450μm / 1000μm
Pixel size	172 x 172 µm²	172 x 172 µm²
Number of modules	1x2	1x3
Format	487 x 407 = 198,209 pixel	487 x 619 = 301,453 pixel
Area	83.8 x 70.0 mm ²	83.8 x 106.5 mm ²
Dynamic range	20 bits (1:1,048,576)	20 bits (1:1,048,576)
Counting rate per pixel	> 2 x 10 ⁶ cps	>2 x 10 ⁶ cps
Energy range	3-30 keV	3-30 keV
Readout time	7 ms	7 ms
Maximum frame rate	20 Hz	20 Hz
Cooling	Air-cooled	Water-cooled

Specifications without obligation and subject to change without notice.

Also available with DECTRIS EIGER2 and PILATUS3 CdTe-Detectors.



STOE & Cie GmbH Hilpertstrasse 10 64295 Darmstadt | Germany

P +49 6151 988 70

F +49 6151 988 788

STOE Corporation 525 West Monroe Street, Suite 2360 Chicago, Illinois 60661 | USA

P +1 312 646 6053

F +1 312 669 1169